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## Positron Annihilation Spectroscopy Measurements for Porosimetry

R. Krause-Rehberg, Dept. of Physics, University Halle



#### Positron Annihilation Lifetime Spectroscopy - PALS



## Digital lifetime measurement



- simple setup
- timing very accurate
- each detector for start & stop (double statistics)

#### Screenshot of two digitized anode pulses

Fullscale: 1, Offset: 0.45, results in [240.976,-	12.6829], ymax: 0.56375, dy: -253.659		
zeroline: 0.0420833			
		$\sim$	
	Minimum at: 41.4432		
Fraction Point: -0.127199	Fraction Point At: 37-5505		
Minimum: -0.522192			
Fullscale: 1. Offset: 0.45. results in 1312.411.16.442711 umak: 0.434944.dvs. 329.954			
Fullscale: 1 Ottset: 0.45 results in 1312.411.	16 / / 7 / mak: 0 / 3/8// dv: _328 85/		
Fullscale: 1, Offset: 0.45, results in [312.411,-	16.4427], ymak: 0.434844, dy: -328.854		
Fullscale: 1, Offset: 0.45, results in [312.411,-	16.4427]; ymak: 0.434844, dy: -328.854 time difference = 2.65471 samples =	= 663.67 ps	
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## Principles of PALS: ortho-Positronium



be formed (Polymers, glass, liquids, gases).

### Principles of PALS: pick-off Annihilation



#### pick-off annihilation:

- o-Ps is converted to p-Ps by capturing an electron with anti-parallel spin
- happens during collisions at walls of pore
- lifetime decreases rapidly
- lifetime is function of pore size 0.5 ns ... 142 ns
- lifetime can be extracted from spectra

# Principles of PALS: typical spectrum



typical lifetime spectrum

Ζ

# PALS: detection limits



- lower detection limit: open volume of 2Å diameter
- e.g. open volume between polymer chains
- upper limit: ≈ 60 nm diameter
- physical limit: vacuum lifetime of o-Ps = 142 ns
- upper limit depends also on corresponding intensity

# New Analysis Technique: MELT



porous polymer

#### MELT<sup>1</sup> = Maximum Entropy for Lifetime Analysis

- number of components must not be known
- output is intensity versus lifetime
- pore size distribution can be determined
- disadvantage: very high statistics necessary (> 10<sup>7</sup> counts)

# The TE model

• Annihilation rate:  $\frac{1}{\tau_{o-Ps}} = \lambda_{o-Ps}$  $= \lambda_{2\gamma} + \lambda_{3\gamma}$  $= \lambda_{2\gamma}^{0}(P) + \lambda_{3\gamma}^{0}(1-P) \cong \lambda_{2\gamma}^{0}(P)$  $\lambda_{2\gamma}^{0} = \frac{\lambda_{S} + 3\lambda_{T}}{4} = \lambda_{A} \approx 2ns^{-1}$ 

Pore size < 1 nm ->  $\lambda_{3\gamma}$  neglected, only pick off annihilation

$$\lambda_{TE}(R) = \lambda_A \left[ 1 - \frac{R}{R + \Delta R} + \frac{1}{2\pi} \sin\left(\frac{2\pi R}{R + \Delta R}\right) \right]$$

- ΔR = 0.166 nm determined by Eldrup and Jean
- Pore size > 1 nm -> $\lambda_{3\gamma}$  cannot be neglected, temperature dependence of o-Ps lifetime (excited states)

#### The TE model (valid until 1 nm radius)



Tao, S. J. J. Chem. Phys. 1972, 56, 5499-5510. / Eldrup, M.; Lightbody, D.; Sherwood, J. N. Chem. Phys. 1981, 63, 51-58.

# The TE model



- TE model valid for r > 2nm
- very successful for open-volume characterization in polymers



Tao, S. J. J. Chem. Phys. 1972, 56, 5499-5510. / Eldrup, M.; Lightbody, D.; Sherwood, J. N. Chem. Phys. 1981, 63, 51-58.

# Polymer research



PALS study of different polymers under CO<sub>2</sub> gas exposure and pressure densified (200 MPa)

G. Dlubek et al., Macromol. Chem. Phys. 2008, 209, 1920–1930 and e-Polymers 2007, no. 108

# Polymer research



**Fig. 5.** The mean,  $\langle v_h \rangle$ , and the mean dispersion,  $\sigma_h$ , of the hole volume as a function of temperature *T* for untreated (black), densified at 200 MPa (blue), and CO<sub>2</sub> gas-exposed and degassed (red) COC and PC.

## Mesopores - Controlled pore glasses



# Controlled pore glasses - CPG

#### **VYCOR-Process**



 $d_P$  1 to 110 nm

- spinodal phase separation
- decomposition is initiated by heat treatment
- alkali rich borate phase <-> pure silica
- alkali phase soluable in acid -> silica network
- pore size depends on basic material
- shape depends on duration and T of heat treatment

## Model for R > 1 nm - RTE

 Rectangular TE model = RTE model (for 3D cubic pores):

$$\frac{del = RTE \text{ model}}{S};$$

$$\lambda_{RTE}(D,T) = \lambda_A - \frac{\lambda_S - \lambda_{3\gamma}}{4} \left[ 1 - \frac{2\delta}{D} + \frac{\sum_{i=1}^{\infty} \frac{1}{i\pi} \sin\left(\frac{2i\pi\delta}{D}\right) e^{\left(\frac{-\beta i^2}{D^2 kT}\right)}}{\sum_{i=1}^{\infty} e^{\left(\frac{-\beta i^2}{D^2 kT}\right)}} \right]^3$$



- Boltzmann statistics ascribes explicit temperature dependence to the lifetime
- Rectangular geometry -> prevention of complicated Bessel functions
- $\delta$ = 0.18 nm analogous to TE model

D. W. Gidley, T. L. Dull, W. E. Frieze, J. N. Sun, A. F. Yee, J. Phys. Chem. B 2001, 105, 4657.

#### The experiments at room temperature



 we measured porous glass in a broad pore size range

- pore size obtained by N<sub>2</sub>adsorption method
- for T=300 K general agreement to the RTE model
- calibration curve for the correlation of o-Ps lifetime and pore size

# The RTE model



**Figure 5** (*Top*) Pore size calibration calculated at different temperatures versus meanfree path. (*Bottom*) Recent round-robin comparisons of PALS pore diameters with those measured by small-angle neutron scattering (SANS), ellipso-metric porosimetry (EP), and gas absorption (BET).

D.W. Gidley et al., Annu. Rev. Mater. Res. 2006. 36:49-79

#### Small pores in the wall of larger pores

Microporous and Mesoporous Materials 182 (2013) 136-146



Transformation of porous glasses into MCM-41 containing geometric bodies

CrossMark

Hans Uhlig<sup>a,\*</sup>, Marie-Luise Gimpel<sup>a</sup>, Alexandra Inayat<sup>b</sup>, Roger Gläser<sup>a</sup>, Wilhelm Schwieger<sup>b</sup>, Wolf-Dietrich Einicke<sup>a</sup>, Dirk Enke<sup>a</sup>

<sup>a</sup> University of Leipzig, Institute of Chemical Technology, Linnéstr. 3, 04103 Leipzig, Germany

<sup>b</sup> University of Erlangen-Nuremberg, Institute of Chemical Reaction Engineering, Egerlandstr. 3, 91058 Erlangen, Germany

Sample	Amount of tenside solution in ml	new sample name
GA-01	40	MCM-40
GA-02	35	MCM-35
GA-03	30	MCM-30
GA-04	42	MCM-42
GA-05	25	MCM-25
GA-06	20	MCM-20
GA-14	10	MCM-10
GA-15	5	MCM-05







Mean implantation depth of un-moderated positrons (1/e): Si: 50µm

## **Moderation of Positrons**



moderation efficiency:  $\approx 10^{-4}$ 

#### HZDR Dresden-Rossendorf: Ground map of the ELBE hall







Martin-Luther-Universität Halle



#### MePS system @ ELBE, 26. November 2013

- modern ultra-large scale microprocessors suffers from long relaxation times
- information transport is limited by product R × C
- R has been decreased: Copper technology (instead of Al)
- C is relatively high when SiO<sub>2</sub> is used as isolation layer;  $\varepsilon_r$ =4

$$C = \frac{\varepsilon_0 \varepsilon_{\rm r} A}{d}$$

- low-k (small  $\varepsilon_r$  = 2...2.5) layers may help
- these are layers with micropores with pore size of d≈1 nm with high porosity
- problem for characterization: closed porosity





Delay as Function of Feature Size



- Positrons are ideal tool for closed porosity in low-k layers
- Lifetime spectra of differently treated low-K layers
- Treatment:
  - untreated porous layer
  - plasma treatment for compactation
  - TiN cap layer



 dispersion of lifetime gives the size distribution of the pore system

Low-K dielectric layers



- monoenergetic positrons can be used to depth scan the layer
  - monoenergetic positrons are obtained by moderation

## Summary

- PALS is a useful porosimetry tool
  - very sensitive method for small pores (0.3 to 10 nm)
  - upper sensitive limit  $\approx 60$  nm
  - non-destructive method
  - Works in open and closed pore systems
  - □ applicable also for thin layers (50 ... 2000 nm)

#### HZDR Dresden-Rossendorf 21.-23. October 2015

#### Workshop

#### **Methods of Porosimetry and Applications**

The workshop will treat aspects of the different methods of porosimetry, such as N<sub>2</sub>-Adsorption, Hg intrusion, SAXS, SANS and Positron Annihilation. Tutorial talks will be given about these topics. The limitations and possible applications of these techniques will be discussed. The workshop will be organized at the Institute of Radiation Physics at HZDR in Dresden-Rossendorf.



"A theory is something nobody believes, except the person who made it. An experiment is something everybody believes, except the person who made it."

Albert Einstein (American German 1879-1955)

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....and more

http://positron.physik.uni-halle.de